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August 2015

FCPF850N80Z — N-Channel SuperFET[®] II MOSFET

FCPF850N80Z

N-Channel SuperFET[®] II MOSFET

800 V, 8 A, 850 m Ω

Features

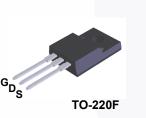
- Typ. R_{DS(on)} = 710 mΩ (Typ.)
- Ultra Low Gate Charge (Typ. Q_g = 22 nC)
- Low E_{oss} (Typ. 2.3 uJ @ 400V)
- Low Effective Output Capacitance (Typ. C_{oss(eff.)} = 106 pF)
- 100% Avalanche Tested
- RoHS Compliant
- ESD Improved Capability

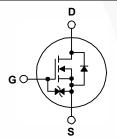
Applications

- AC DC Power Supply
- LED Lighting

Description

SuperFET[®] II MOSFET is Fairchild Semiconductor's brand-new high voltage super-junction (SJ) MOSFET family that is utilizing charge balance technology for outstanding low on-resistance and lower gate charge performance. This technology is tailored to minimize conduction loss, provide superior switching performance, dv/dt rate and higher avalanche energy. In addition, internal gate-source ESD diode allows to withstand over 2kV HBM surge stress. Consequently, SuperFET II MOSFET is very suitable for the switching power applications such as Audio, Laptop adapter, Lighting, ATX power and industrial power applications.





Absolute Maximum Ratings T_C = 25°C unless otherwise noted.

Symbol		FCPF850N802	Z Unit	
V _{DSS}	Drain to Source Voltage	800	V	
V _{GSS}		- DC	±20	V
	Gate to Source Voltage	- AC (f > 1	l Hz) ±30	V
ID	Drain Current	- Continuous (T _C = 25 ^o C)	8.0*	А
		- Continuous (T _C = 100 ^o C)	5.1*	A
I _{DM}	Drain Current	- Pulsed (N	lote 1) 18*	A
E _{AS}	Single Pulsed Avalanche Ener	lote 2) 114	mJ	
I _{AR}	Avalanche Current	lote 1) 1.2	A	
E _{AR}	Repetitive Avalanche Energy	lote 1) 0.284	mJ	
dv/dt	MOSFET dv/dt	100	V/ns	
	Peak Diode Recovery dv/dt	lote 3) 20	V/IIS	
P _D	Dower Discinction	(T _C = 25°C)	28.4	W
	Power Dissipation	- Derate Above 25°C	0.24	W/ºC
T _J , T _{STG}	Operating and Storage Tempe	-55 to +150	°C	
TL	Maximum Lead Temperature f	300	°C	

*Drain current limited by maximum junction temperature, with heatsink.

Thermal Characteristics

Symbol	Parameter	FCPF850N80Z	Unit
$R_{\theta JC}$	Thermal Resistance, Junction to Case, Max.	4.4	°C/W
$R_{ extsf{ heta}JA}$	Thermal Resistance, Junction to Ambient, Max.	62.5	°C/W

Part Nur	nber	Top Mark	Package	Packing Method	Reel Si	ze	Tape Widt	h Qi	uantity	
FCPF850	N80Z	FCPF850N80Z	TO-220F	· ·			N/A		50 units	
Electrica	l Char	acteristics T _C = 25°C	unless oth	erwise noted.		L				
Symbol		Parameter		Test Conditions	Mi		Тур.	Max.	Unit	
Off Charac	teristic	S								
BV _{DSS}	Drain to Source Breakdown Voltage		V _{GS} =	V _{GS} = 0 V, I _D = 1 mA, T _J = 25°C			-	-	V	
ΔBV _{DSS} / ΔT _J	Breakdown Voltage Temperature Coefficient		I _D = 1	$I_D = 1$ mA, Referenced to 25°C			0.8	-	V/ºC	
	Zero G	Zara Cata Valtaga Drain Current		V_{DS} = 800 V, V_{GS} = 0 V V_{DS} = 640 V, V_{GS} = 0 V, T_C = 125°C			-	25	μΑ	
I _{DSS}	Zero Gate Voltage Drain Current						-	250		
I _{GSS}	Gate to	Body Leakage Current	V _{GS} =	$V_{GS} = \pm 20 V, V_{DS} = 0 V$			-	±10	μA	
On Charac	teristic	s								
V _{GS(th)}	Gate T	hreshold Voltage	V _{GS} =	V _{DS} , I _D = 0.6 mA		2.5	-	4.5	V	
R _{DS(on)}	Static D	Frain to Source On Resistance	e V _{GS} =	10 V, I _D = 3 A		-	710	850	mΩ	
9 _{FS}	Forwar	d Transconductance	V _{DS} =	20 V, I _D = 3 A		-	3.5	-	S	
Dynamic C	haract	oristics								
•		apacitance					990	1315	۳E	
C _{iss}		Capacitance	V _{DS} =	100 V, V _{GS} = 0 V,	-		28	37	pF pF	
C _{oss} C _{rss}		e Transfer Capacitance	f = 1 N	f = 1 MHz		-	0.74	57	pF	
C _{oss}		Capacitance	Vno =	480 V, V _{GS} = 0 V, f =	1 MHz	-	15	_	pF	
C _{oss(eff.)}		e Output Capacitance		$0 \text{ V to } 480 \text{ V}, \text{ V}_{GS} = 0$		-	106	-	pF	
Q _{g(tot)}		ate Charge at 10V		$V_{DS} = 640 \text{ V}, V_{GS} = 6 \text{ V}$ $V_{DS} = 640 \text{ V}, I_D = 6 \text{ A},$ $V_{GS} = 10 \text{ V}$ (Note 4)		-	22	29	nC	
Q _{gs}		Source Gate Charge				-	5	-	nC	
Q _{gd}		Drain "Miller" Charge				-	8.6	-	nC	
ESR		ent Series Resistance	f = 1 N	ИНz		-	2.4	-	Ω	
Switching	Charac	toristics								
•		n Delay Time				-	16	42	ns	
t _{d(on)} t _r		n Rise Time	Vpp =	V_{DD} = 400 V, I _D = 6 A, V_{GS} = 10 V, R _g = 4.7 Ω (Note 4)		-	10	30	ns	
t _{d(off)}		f Delay Time				-	40	90	ns	
t _f		f Fall Time					4.5	19	ns	
					(1010-1)				1	
		de Characteristics	o Diada E	anward Current			-	8	•	
I _S		Maximum Continuous Drain to Source Diode Forward Current Maximum Pulsed Drain to Source Diode Forward Current				-	-	18	A	
I _{SM} V _{SD}		Source Diode Forward Volta		= 0 V, I _{SD} = 6 A		-		1.2	V	
t _{rr}		Recovery Time		: 0 V, I _{SD} = 6 A,		_	318	-	ns	
Q _{rr}		Recovery Charge		= 100 A/μs	-	_	4.5	-	μΟ	
lotes:	100000						1.0		μΟ	
	: pulse width	limited by maximum junction temperat	ure.							
		= 25 Ω , Starting T _J = 25°C								

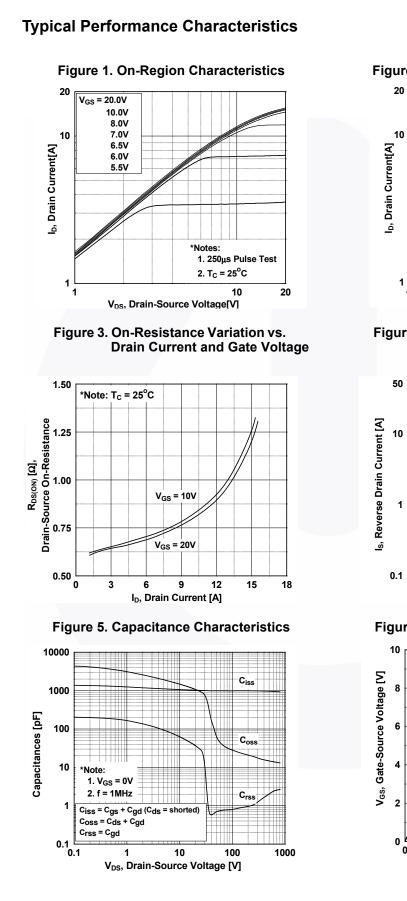


Figure 2. Transfer Characteristics

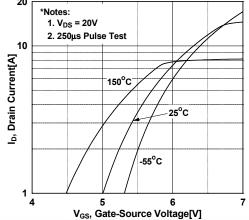


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

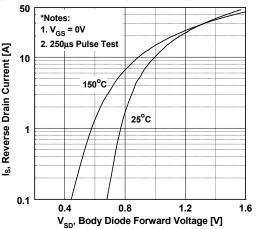
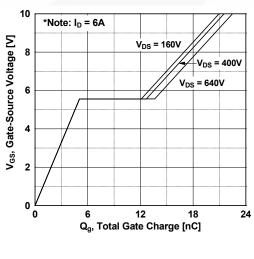
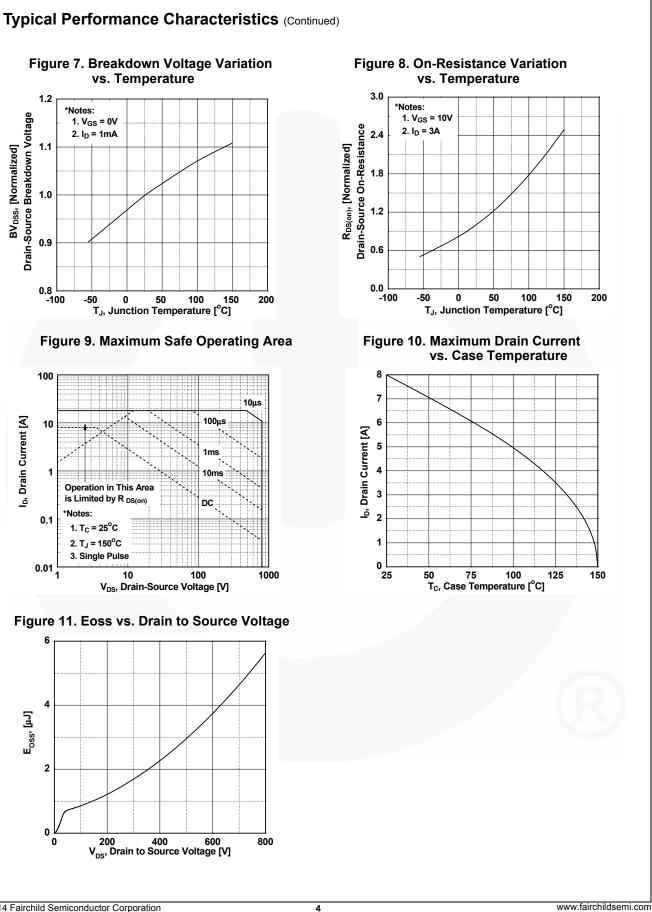
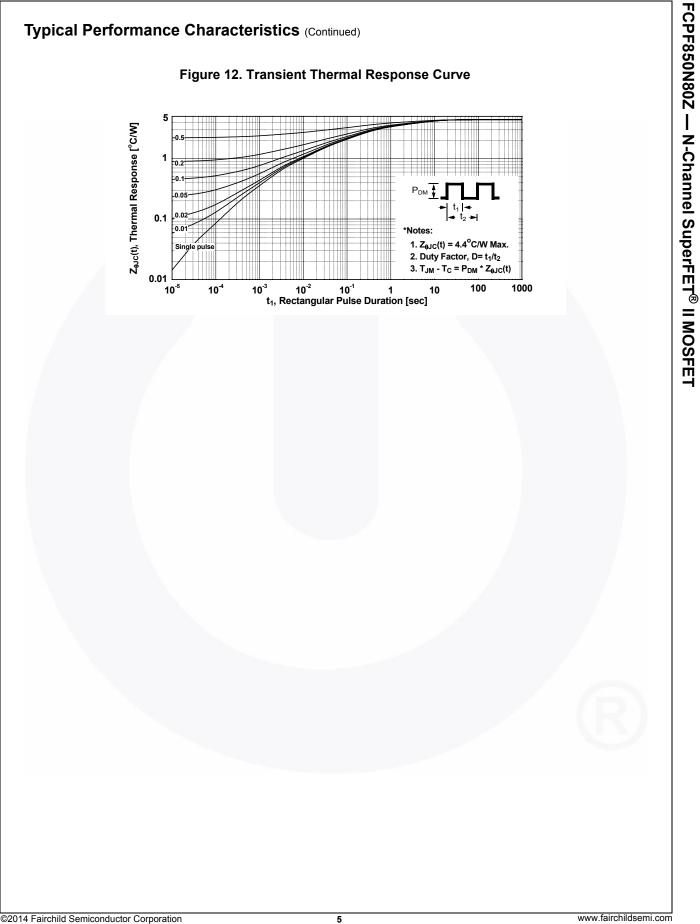


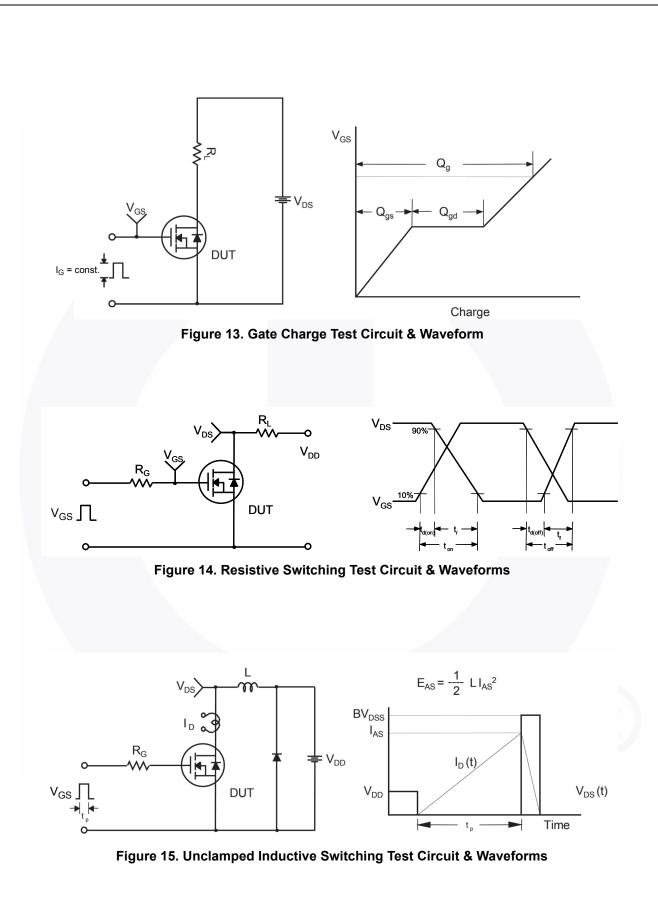
Figure 6. Gate Charge Characteristics





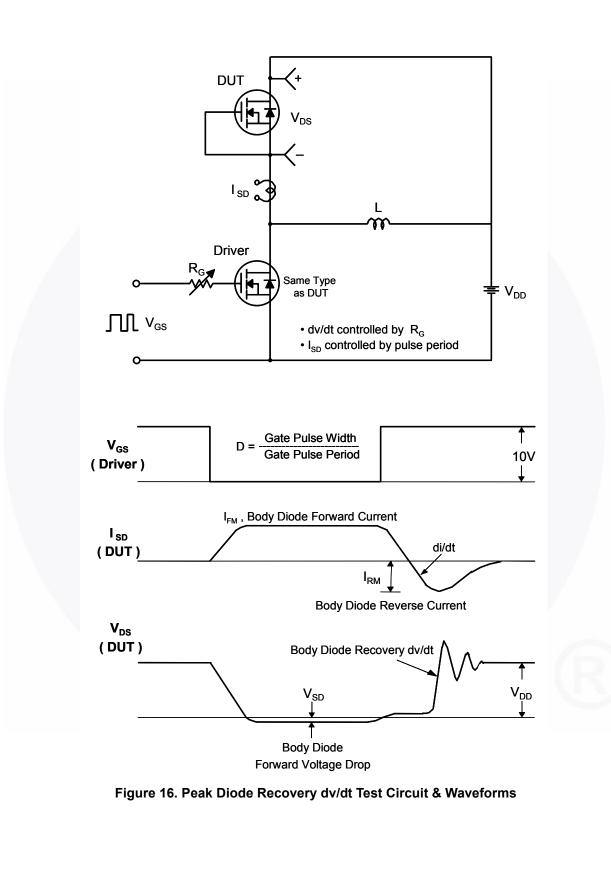
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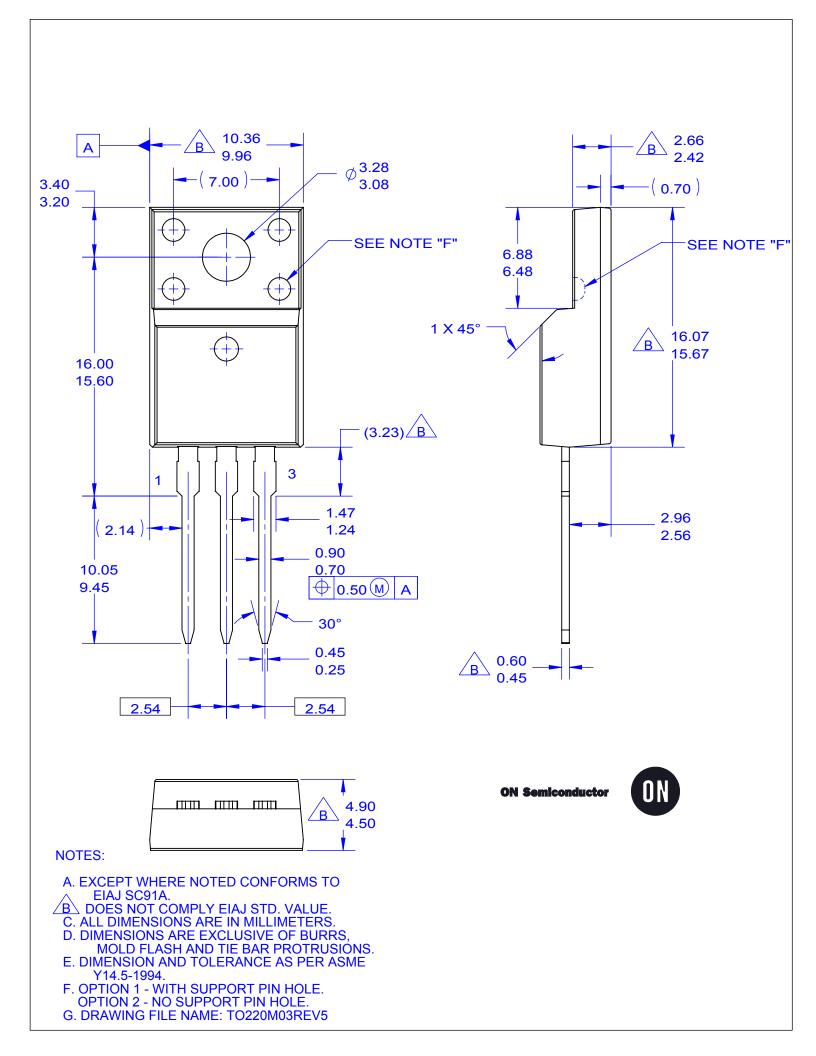




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